"Application No. 10/606,715 Attny Docket: 200312936-1

AMENDMENTS TO THE SPECIFICATION

Please replace the Title of the Invention with the following amended Title:

-- Methods And Systems For Masking Faults In A Margin Testing Environment--

Please replace the paragraph at page 1, line 5 to line 16, with the following amended paragraph:

The present application is related to the following commonly owned U.S. Patent Applications, incorporated in their entirety herein by reference:

U.S. Patent Application No. 10/606,463 filed June 26, 2003, entitled "USE OF I²C-BASED POTENTIOMETERS TO ENABLE VOLTAGE RAIL VARIATION UNDER BMC CONTROL," naming as inventors Benjamin T. Percer, Naysen J. Robertson and Akbar Monfared (Attorney Docket No.: 200208051-1); U.S. Patent Application No. 10/606,714 filed June 26, 2003, entitled "METHOD AND CONSTRUCT FOR ENABLING PROGRAMMABLE, INTEGRATED SYSTEM MARGIN TESTING" naming as inventors Naysen J. Robertson, Benjamin T. Percer and Sachin N. Chheda (Attorney Docket No.: 200207937-1); and U.S. Patent Application No. 10/606,713 filed June 26, 2003, entitled "USE OF I²C PROGRAMMABLE CLOCK GENERATOR TO ENABLE FREQUENCY VARIATION UNDER BMC CONTROL," naming as inventors Naysen J. Robertson, Benjamin T. Percer, and Kirk Yates (Attorney Docket No.: 200208055-1).